

MOSFETs Silicon P-/N-Channel MOS

SSM6L820R

1. Applications

· Power Management Switches

2. Features

- (1) AEC-Q101 qualified (Please see the orderable part number list)
- (2) Low drain-source on-resistance

Q1 N-channel:

 $R_{\mathrm{DS(ON)}}$ = 39.1 m Ω (max) (@ V_{GS} = 4.5 V)

 $R_{\rm DS(ON)} = 53 \, {\rm m}\Omega \, ({\rm max}) \, (@V_{\rm GS} = 2.5 \, {\rm V})$

 $R_{\rm DS(ON)} = 82 \ {\rm m}\Omega \ ({\rm max}) \ (@V_{\rm GS} = 1.8 \ {\rm V})$

Q2 P-channel:

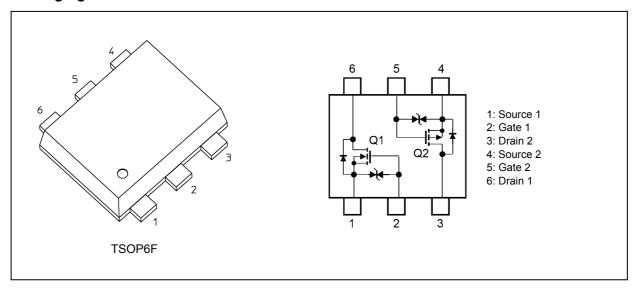
 $R_{DS(ON)} = 45 \text{ m}\Omega \text{ (max) } (@V_{GS} = -10 \text{ V})$

 $R_{\mathrm{DS(ON)}} = 56 \ \mathrm{m}\Omega \ (\mathrm{max}) \ (\mathrm{@V_{\mathrm{GS}}} = \text{-}4.5 \ \mathrm{V})$

 $R_{DS(ON)}$ = 76 m Ω (max) (@V_{GS} = -2.5 V)

 $R_{DS(ON)} = 157 \text{ m}\Omega \text{ (max) } (@V_{GS} = -1.8 \text{ V})$

3. Packaging and Internal Circuit



4. Orderable part number

Orderable part number	AEC-Q101		Note		
SSM6L820R,LF	_		General Use		
SSM6L820R,LXGF	YES	(Note 1)	Unintended Use	(Note 1)	
SSM6L820R,LXHF	YES		Automotive Use		

Note 1: For more information, please contact our sales or use the inquiry form on our website.

Start of commercial production

2018-11



5. Absolute Maximum Ratings (Note)

5.1. Q1 Absolute Maximum Ratings (Unless otherwise specified, Ta = 25 °C)

Characteristics				Rating	Unit
Drain-source voltage			V_{DSS}	30	V
Gate-source voltage			V _{GSS}	+12/-8	
Drain current (DC)	,	(Note 1)	I _D	4	Α
Drain current (pulsed)	(t ≤ 10 ms)	(Note 1), (Note 2)	I _{DP}	10]

Note 1: Ensure that the channel temperature does not exceed 150 °C.

Note 2: Pulse width (PW) \leq 10 ms, duty \leq 1 %

5.2. Q2 Absolute Maximum Ratings (Unless otherwise specified, Ta = 25 °C)

Characteristics				Rating	Unit
Drain-source voltage			V_{DSS}	-20	V
Gate-source voltage	,		V_{GSS}	-12/+6	
Drain current (DC)	,	(Note 1)	I _D	-4	Α
Drain current (pulsed)	(t ≤ 10 ms)	(Note 1), (Note 2)	I _{DP}	-10	

Note 1: Ensure that the channel temperature does not exceed 150 °C.

Note 2: Pulse width (PW) \leq 10 ms, duty \leq 1 %

5.3. Absolute Maximum Ratings (Unless otherwise specified, T_a = 25 °C) (Q1, Q2 Common)

	Characteristics		Symbol	Rating	Unit
Power dissipation		(Note 1)	P _D	1.4	W
Power dissipation	(t ≤ 10 s)	(Note 1)		1.8	
Channel temperature			T _{ch}	150	°C
Storage temperature			T _{stg}	-55 to 150	

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 1: Device mounted on an FR4 board.(total rating)

 $(25.4 \text{ mm} \times 25.4 \text{ mm} \times 1.6 \text{ mm}, \text{ Cu pad: } 645 \text{ mm}^2)$

Note: The MOSFETs in this device are sensitive to electrostatic discharge. When handling this device, the worktables, operators, soldering irons and other objects should be protected against anti-static discharge.

Note: The channel-to-ambient thermal resistance, R_{th(ch-a)}, and the drain power dissipation, P_D, vary according to the board material, board area, board thickness and pad area. When using this device, be sure to take heat dissipation fully into account.

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6. Electrical Characteristics

6.1. Q1 Static Characteristics (Unless otherwise specified, Ta = 25 °C)

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current		I _{GSS}	V _{DD} = 0 V, V _{GS} = 10/-8 V	_	_	±10	μΑ
Drain cut-off current		I _{DSS}	V _{DS} = 24 V, V _{GS} = 0 V	_		1	
Drain-source breakdown voltage	·	V _{(BR)DSS}	I _D = 1 mA, V _{GS} = 0 V	30	_		V
Drain-source breakdown voltage	(Note 1)	$V_{(BR)DSX}$	I _D = 1 mA, V _{GS} = -12 V	18	_		
Gate threshold voltage	(Note 2)	V_{th}	V _{DS} = 3 V, I _D = 1 mA	0.4	_	1	
Drain-source on-resistance	(Note 3)	R _{DS(ON)}	I _D = 2.0 A, V _{GS} = 4.5 V	_	30	39.1	mΩ
			I _D = 1.0 A, V _{GS} = 2.5 V	_	37	53	
			I _D = 0.5 A, V _{GS} = 1.8 V	_	46	82	

Note 1: If a reverse bias is applied between gate and source, this device enters $V_{(BR)DSX}$ mode. Note that the drain-source breakdown voltage is lowered in this mode.

Note 2: Let V_{th} be the voltage applied between gate and source that causes the drain current (I_D) to below (1 mA for this device). Then, for normal switching operation, $V_{GS(ON)}$ must be higher than V_{th} , and $V_{GS(OFF)}$ must be lower than V_{th} . This relationship can be expressed as: $V_{GS(OFF)} < V_{th} < V_{GS(ON)}$.

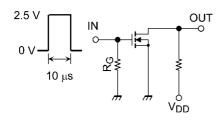
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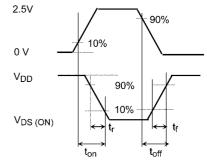
Note 3: Pulse measurement.

6.2. Q1 Dynamic Characteristics (Unless otherwise specified, T_a = 25 °C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Input capacitance	C _{iss}	V _{DS} = 15 V , V _{GS} = 0 V,	_	310	_	pF
Reverse transfer capacitance	C _{rss}	f = 1 MHz	_	20		
Output capacitance	C _{oss}		_	52	_	
Switching time (turn-on time)	t _{on}	V_{DD} = 15 V, I_{D} = 1 A, V_{GS} = 0 to 2.5 V, R_{G} = 4.7 Ω	_	26	_	ns
Switching time (turn-off time)	t _{off}	Duty ≤ 1%, V _{IN} : tr, tf < 5 ns Common source	_	17.0	_	

6.3. Q1 Switching Time Test Circuit





Switching Time Test Circuit

Input Waveform/Output Waveform

6.4. Q1 Gate Charge Characteristics (Unless otherwise specified, T_a = 25 °C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Total gate charge (gate-source plus gate-drain)	Q_g	V _{DD} = 15 V, I _D = 4.0 A,	_	3.2	_	nC
Gate-source charge 1	Q _{gs1}	$V_{GS} = 4.5 V$	_	0.5	_	
Gate-drain charge	Q _{gd}		_	0.7	_	

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2021-06-03



6.5. Q1 Source-Drain Characteristics (Unless otherwise specified, Ta = 25 °C)

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Diode forward voltage	(Note 1)	V_{DSF}	$I_D = -4 A, V_{GS} = 0 V$		-0.8	-1.2	V

Note 1: Pulse measurement.

6.6. Q2 Static Characteristics (Unless otherwise specified, Ta = 25 °C)

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current		I _{GSS}	V _{DS} = 0 V, V _{GS} = +6/-10 V	_	_	±1	μА
Drain cut-off current		I _{DSS}	V _{DS} = -20 V, V _{GS} = 0 V	_	_	-1	
Drain-source breakdown voltage	·	V _{(BR)DSS}	I _D = -1 mA, V _{GS} = 0 V	-20	_	_	V
Drain-source breakdown voltage	(Note 1)	V _{(BR)DSX}	I _D = -1 mA, V _{GS} = 8 V	-12	_	_	
Gate threshold voltage	(Note 2)	V_{th}	$V_{DS} = -3 \text{ V}, I_{D} = -1 \text{ mA}$	-0.5	_	-1.2	
Drain-source on-resistance	(Note 3)	R _{DS(ON)}	I _D = -3.5 A, V _{GS} = -10 V	_	36	45	mΩ
			$I_D = -3.0 \text{ A}, V_{GS} = -4.5 \text{ V}$	_	44	56	mΩ
			I _D = -2.0 A, V _{GS} = -2.5 V	_	60	76	
			I _D = -0.5 A, V _{GS} = -1.8 V		83	157	

Note 1: If a reverse bias is applied between gate and source, this device enters $V_{(BR)DSX}$ mode. Note that the drain-source breakdown voltage is lowered in this mode.

Note 2: Let V_{th} be the voltage applied between gate and source that causes the drain current (I_D) to below (-1 mA for this device). Then, for normal switching operation, $V_{GS(ON)}$ must be higher than V_{th} , and $V_{GS(OFF)}$ must be lower than V_{th} . This relationship can be expressed as: $V_{GS(OFF)} < V_{th} < V_{GS(ON)}$.

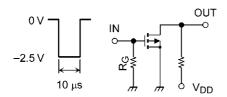
Take this into consideration when using the device.

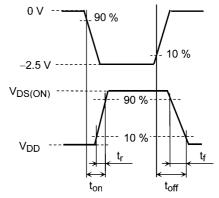
Note 3: Pulse measurement.

6.7. Q2 Dynamic Characteristics (Unless otherwise specified, Ta = 25 °C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Input capacitance	C _{iss}	V _{DS} = -10 V , V _{GS} = 0 V,	_	480		pF
Reverse transfer capacitance	C _{rss}	f = 1 MHz		76		
Output capacitance	C _{oss}		_	90		
Switching time (turn-on time)	t _{on}	V_{DD} = -10 V, I_{D} = -0.5 A, V_{GS} = 0 to -2.5 V, R_{G} = 4.7 Ω		21		ns
Switching time (turn-off time)	t _{off}	Duty \leq 1 %, V_{IN} : t_r , t_f < 5 ns, Common source		54		

6.8. Q2 Switching Time Test Circuit





Switching Time Test Circuit

Input Waveform/Output Waveform



6.9. Q2 Gate Charge Characteristics (Unless otherwise specified, Ta = 25 °C)

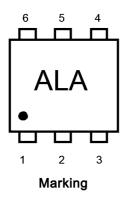
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Total gate charge (gate-source plus gate-drain)		$V_{DD} = -10 \text{ V}, I_D = -4.0 \text{ A},$	_	6.7	_	nC
Gate-source charge 1	Q _{gs1}	V _{GS} = -4.5 V	_	0.95	_	
Gate-drain charge	Q _{gd}		_	1.50	_	

6.10. Q2 Source-Drain Characteristics (Unless otherwise specified, Ta = 25 °C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Diode forward voltage (Note	1) V _{DSF}	I _D = 4 A, V _{GS} = 0 V	_	0.87	1.2	V

Note 1: Pulse measurement.

7. Marking





8. Characteristics Curves (Note)

8.1. Q1 Characteristics Curves

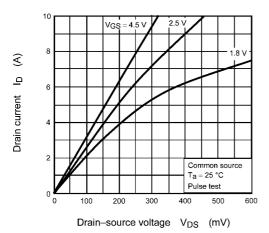


Fig. 8.1.1 I_D - V_{DS}

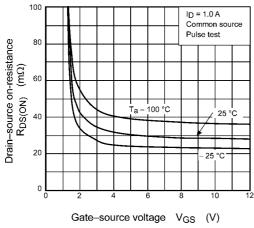


Fig. 8.1.3 R_{DS(ON)} - V_{GS}

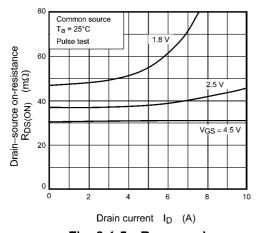


Fig. 8.1.5 R_{DS(ON)} - I_D

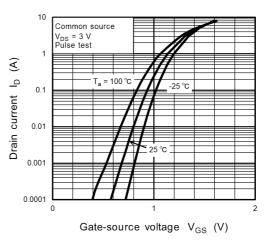


Fig. 8.1.2 I_D - V_{GS}

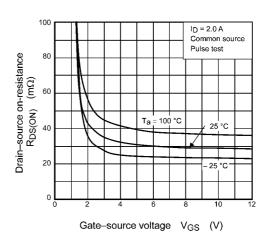


Fig. 8.1.4 R_{DS(ON)} - V_{GS}

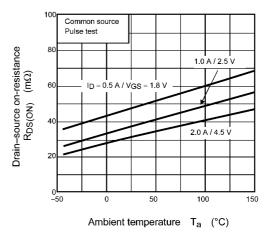
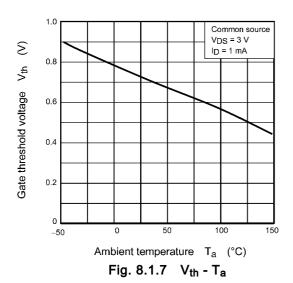


Fig. 8.1.6 R_{DS(ON)} - T_a





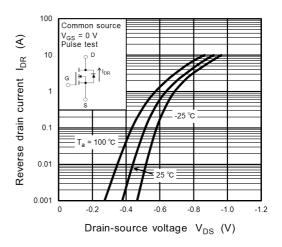


Fig. 8.1.8 I_{DR} - V_{DS}

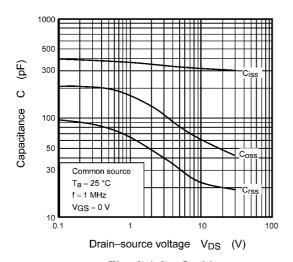


Fig. 8.1.9 C - V_{DS}

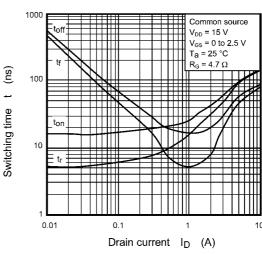


Fig. 8.1.10 t - I_D

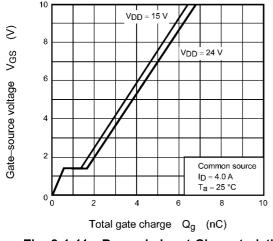


Fig. 8.1.11 Dynamic Input Characteristics

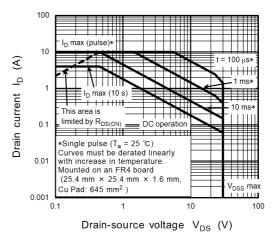


Fig. 8.1.12 Safe Operating Area



8.2. Q2 Characteristics Curves

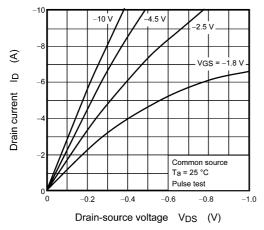


Fig. 8.2.1 I_D - V_{DS}

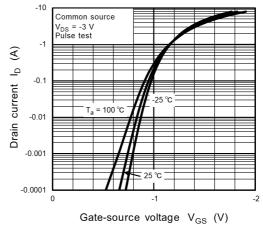


Fig. 8.2.2 I_D - V_{GS}

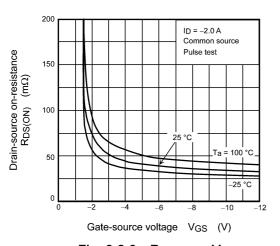


Fig. 8.2.3 R_{DS(ON)} - V_{GS}

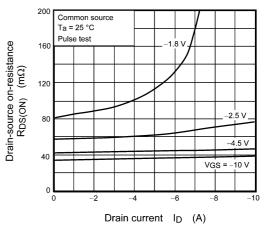


Fig. 8.2.4 R_{DS(ON)} - I_D

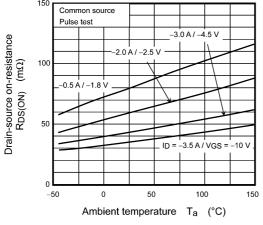


Fig. 8.2.5 R_{DS(ON)} - T_a

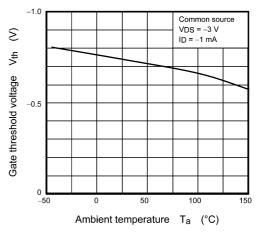


Fig. 8.2.6 V_{th} - T_a

Rev.3.0



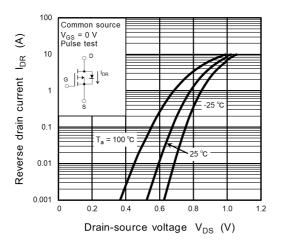


Fig. 8.2.7 IDR - VDS

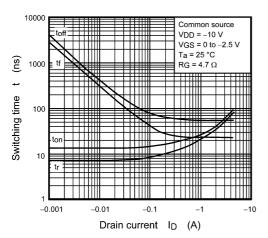


Fig. 8.2.9 t - I_D

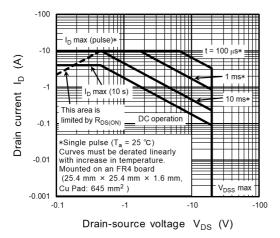


Fig. 8.2.11 Safe Operating Area

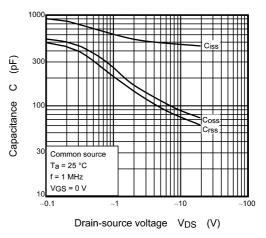


Fig. 8.2.8 C - V_{DS}

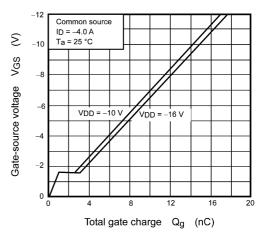
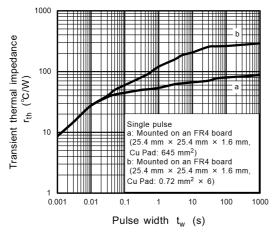


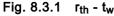
Fig. 8.2.10 Dynamic Input Characteristics

Rev.3.0



8.3. Characteristics Curves (Q1, Q2 Common)





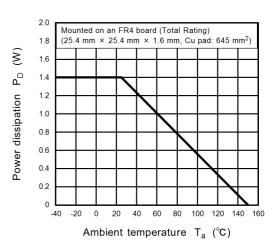


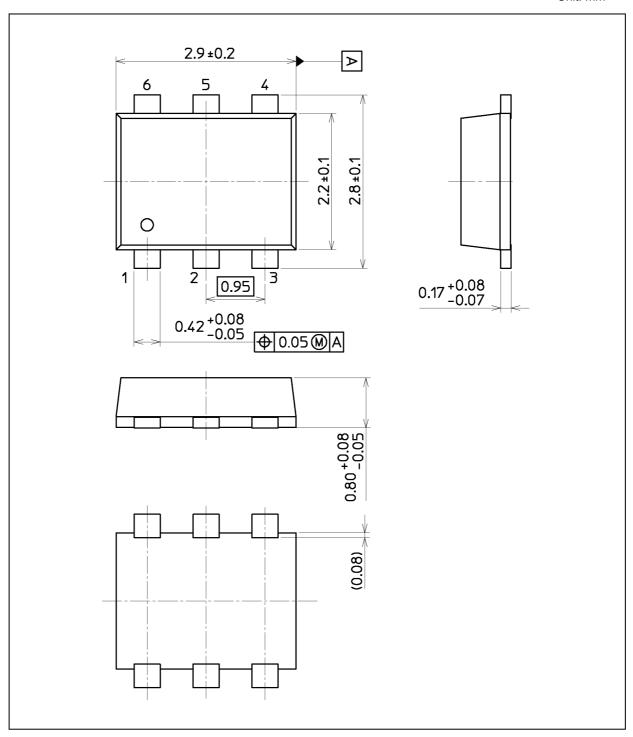
Fig. 8.3.2 P_D - T_a

Note: The above characteristics curves are presented for reference only and not guaranteed by production test, unless otherwise noted.



Package Dimensions

Unit: mm



Weight: 0.016 g (typ.)

Package Name(s)
Nickname: TSOP6F



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